

FORM PTO 1449 (modified)			ATTY DOCKET NO. 03560.003310		APPLICATION NO. 10/601,777		
U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE  LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)			APPLICANT Tadashi Okamoto et al.				
AUG 24 2003 U.S. PATENT & TRADEMARK OFFICE			FILING DATE June 24, 2003		GROUP 1631		
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
EDJ		5,633,495	05/27/97	Neihuis et al.	250	287	
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FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
EDJ	JP	60-49252	03/18/85	Japan			Abstract
	JP	9-500486	01/14/97	Japan			Translation
✓	JP	7-151836	06/16/95	Japan			Translation
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OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)							
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EXAMINER				DATE CONSIDERED	02/17/2006		

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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## APPLICANT

**Tadashi Okamoto et al.**

## FILING DATE

**June 24, 2003**

## GROUP

**1631**

## U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
EDJ	5,589,685	12/31/96	Jen Wu et al.	250	282	
	6,002,128	12/14/99	Hill et al.	250	287	
	2001/0055813 A1	12/27/01	Winograd et al.	436	89	
	5,821,060	10/13/98	Arlinghaus et al.	435	6	
	2002/0074517 A1	06/20/02	Krutchinsky et al.	250	492.1	
	4,983,831	01/08/91	Migeon et al.	250	309	

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
EDJ	DE	31 44 604 A1	05/19/83	Germany			Abstract

## OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)

EDJ	Steven M. Hues et al., "A Pulsed Alkali-Ion Gun for Time-of-Flight Secondary Ion Mass Spectrometry," 60(7) Rev. Sci. Instrum. 1239-44 (July 1989).
	Viswanatham Katta et al., "A Pulsed Ion Bombardment Time-of-Flight Mass Spectrometer with High Sensitivity for the Analysis of Peptides," 105 Int. J. Mass Spectrom. Ion Processes 129-45 (1991).
	J. Schwieters et al., "High Mass Resolution Surface Imaging with Time-of-Flight Secondary Ion Mass Spectroscopy Scanning Microprobe," 9(6) J. Vac. Sci. Technol. 2864-71 (1991).
	Robert W. Odom, "Secondary Ion Mass Spectrometry Imaging," 29(1) Appl. Spectros. Rev. 67-116 (February 1994).

EXAMINER

*Edj*

DATE CONSIDERED

*02/17/2005*

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	G.C. Rider et al., "Imaging Time-of-Flight SIMS - A New Technique for Spatially-Resolved Chemical Surface Analysis," 4(1) J. Molecul. Electron. 402 (1988) (Abstract).					
	Anthony J. Nicola et al., "Enhancement of Ion Intensity in Time-of-Flight Secondary-Ionization Mass Spectrometry," 7 J. Am. Soc. Mass Spectrom. 467-71 (1996).					
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**Form #62**

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